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(54) **MONOLITHIC FREQUENCY SELECTIVE COMPONENT AND METHOD OF OPERATING SAME**

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(52) **U.S. Cl.** **330/305**

(58) **Field of Search** 330/277, 302, 330/305, 307, 310, 311

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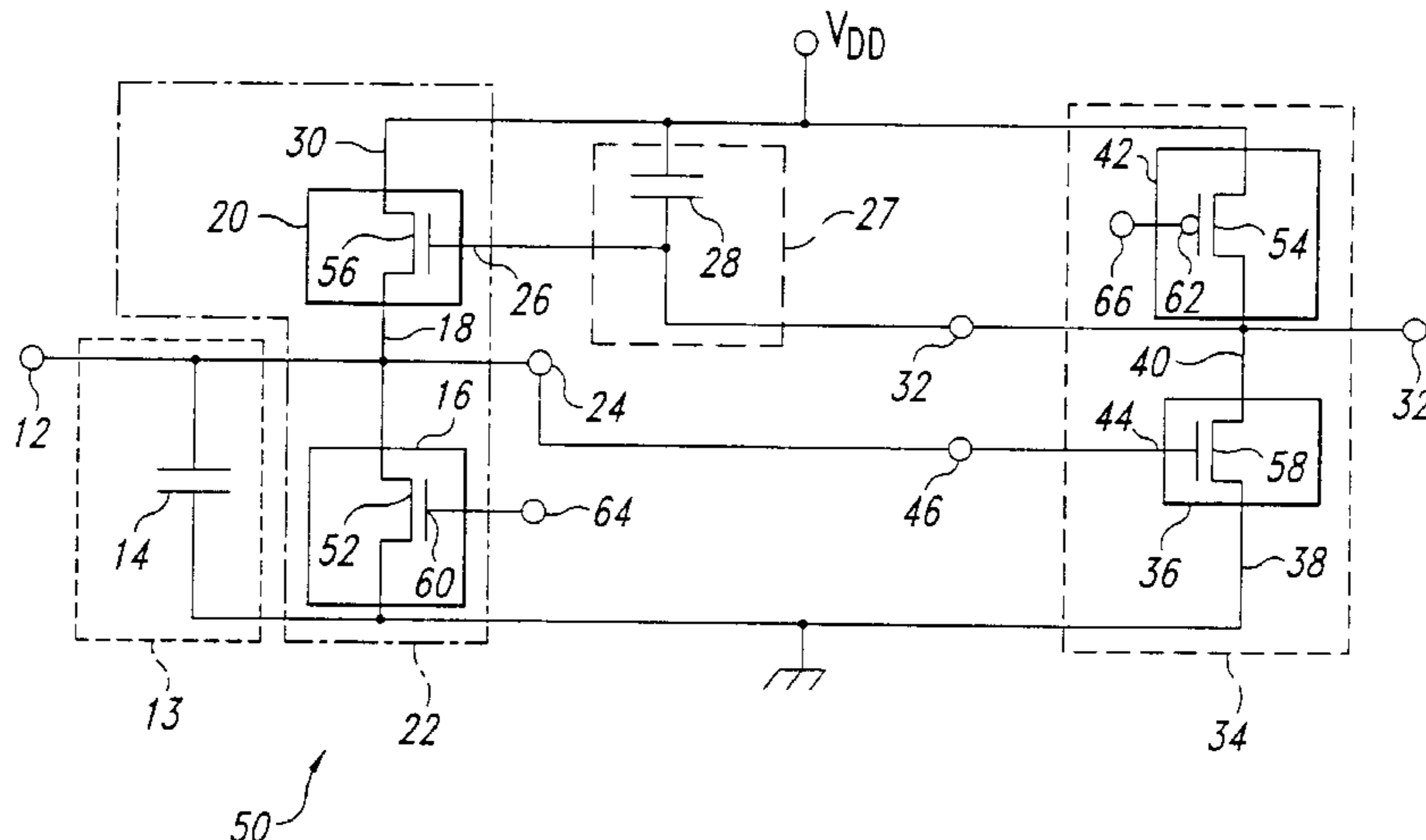
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(57) **ABSTRACT**

A monolithic active frequency selection circuit includes an input presenting a frequency-dependent impedance and a first gain block configured to provide less than unity voltage gain, a high input impedance and a low output impedance. An output of the first amplifier is coupled to the frequency selection circuit input. The frequency selection circuit includes a first phase shifter that, in one aspect, is formed by a first capacitor coupled between the first port and a reference voltage. The frequency selection circuit also includes a second amplifier configured to provide greater than unity voltage gain. The second amplifier has an input coupled to the output of the first amplifier and an output coupled to the input of the first amplifier. The frequency selection circuit further includes a second phase shifter, which may be formed from a capacitor coupled between the output of the second amplifier and a reference voltage. The first and second amplifiers and the first and second phase shifters are coupled in a loop such that the frequency dependence of an impedance presented at the output of the first amplifier emulates the impedance of a parallel RLC tank circuit, providing a Q on the order of ten at a center frequency ω_0 of several hundred megahertz. The output of the second amplifier may be used to provide a high Q, tuned transimpedance amplification function relative to the input.

15 Claims, 5 Drawing Sheets



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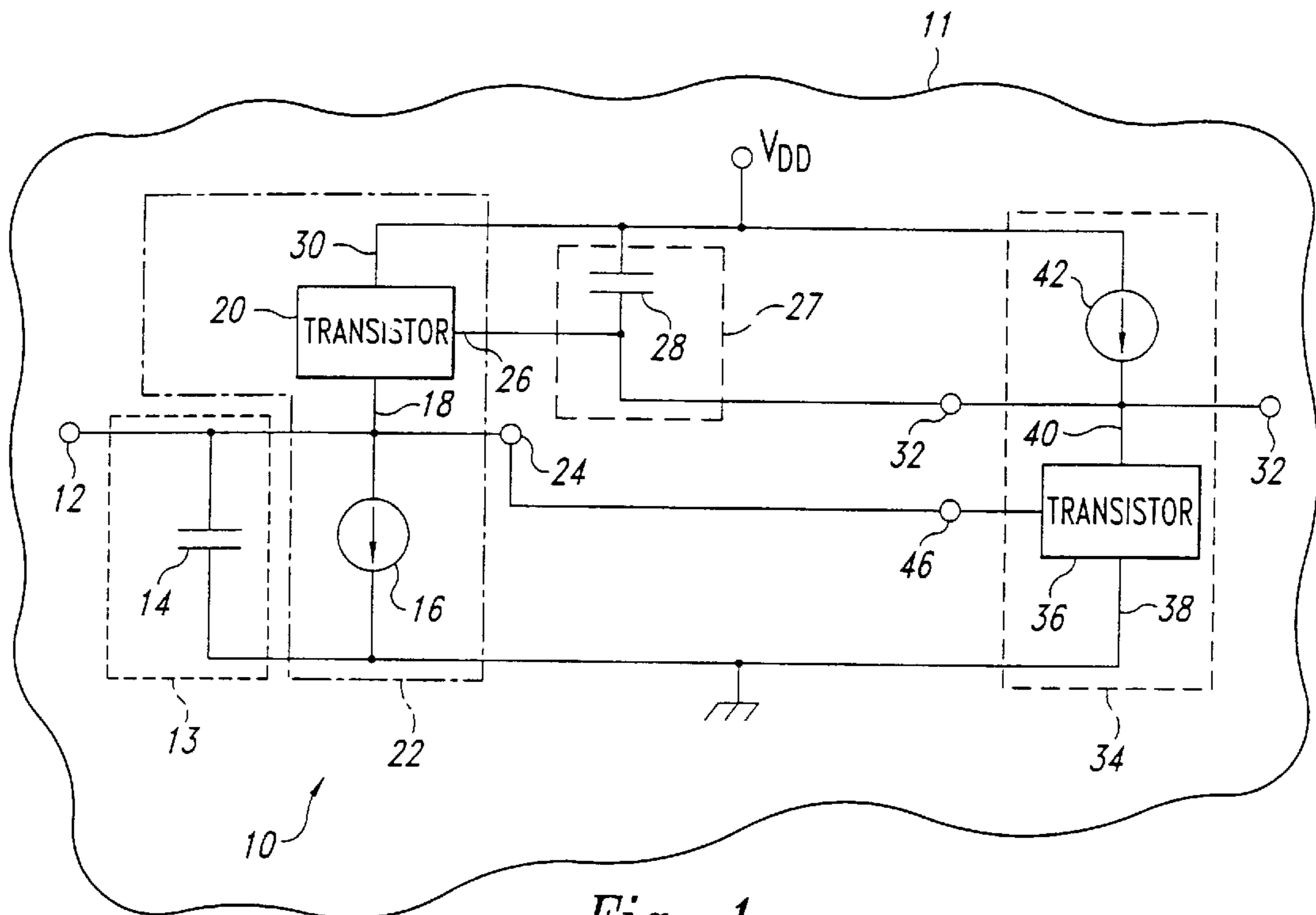


Fig. 1

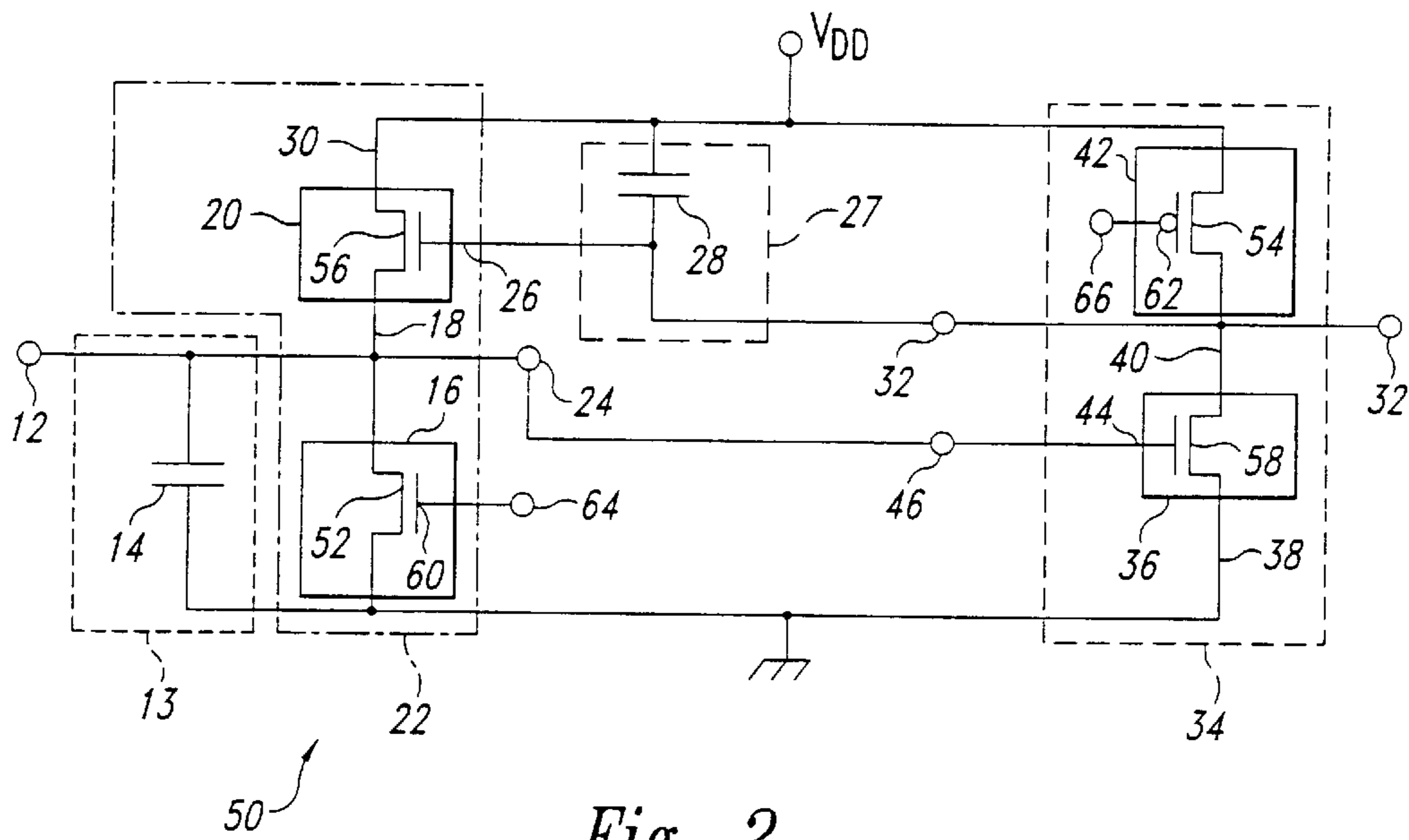


Fig. 2

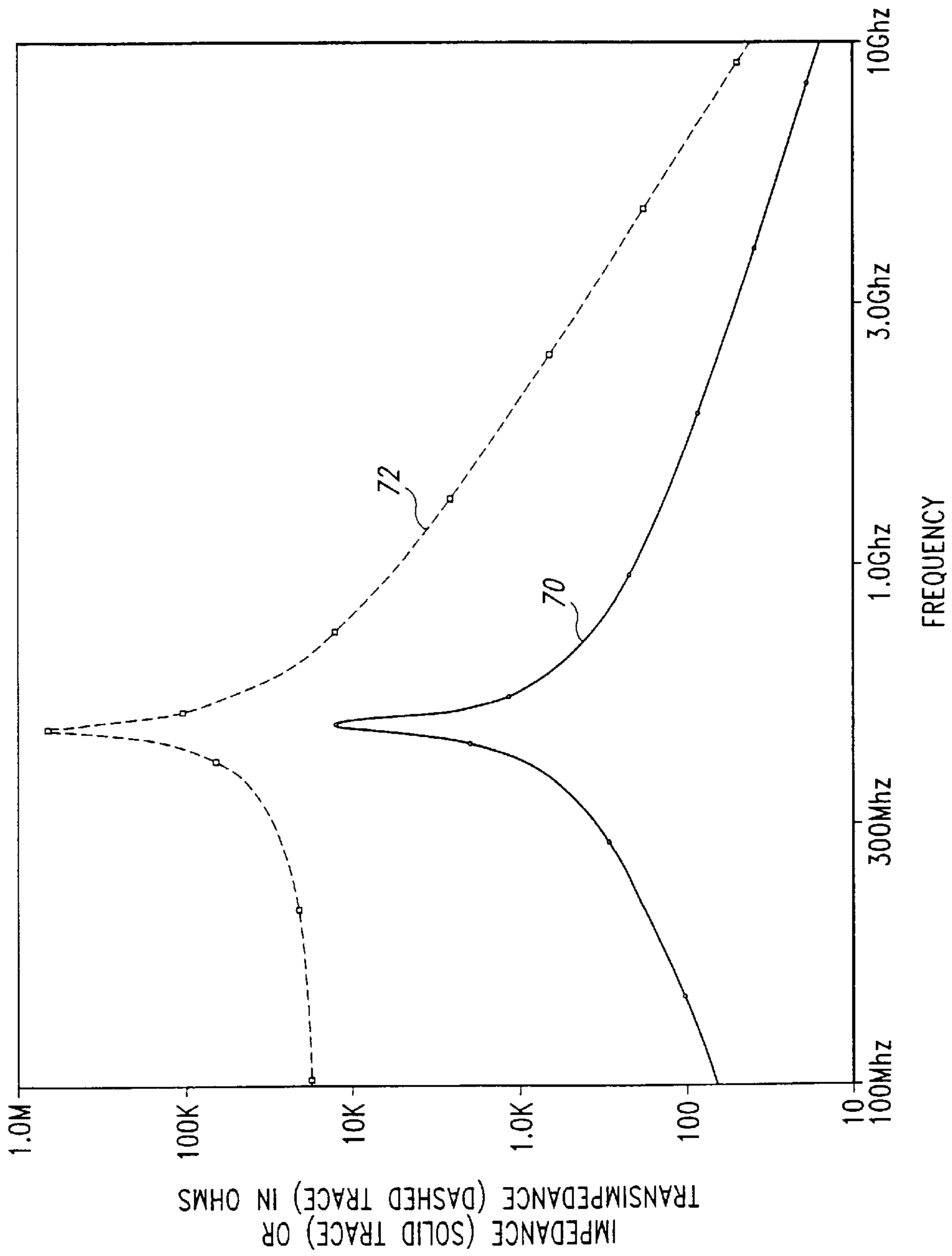


Fig. 3

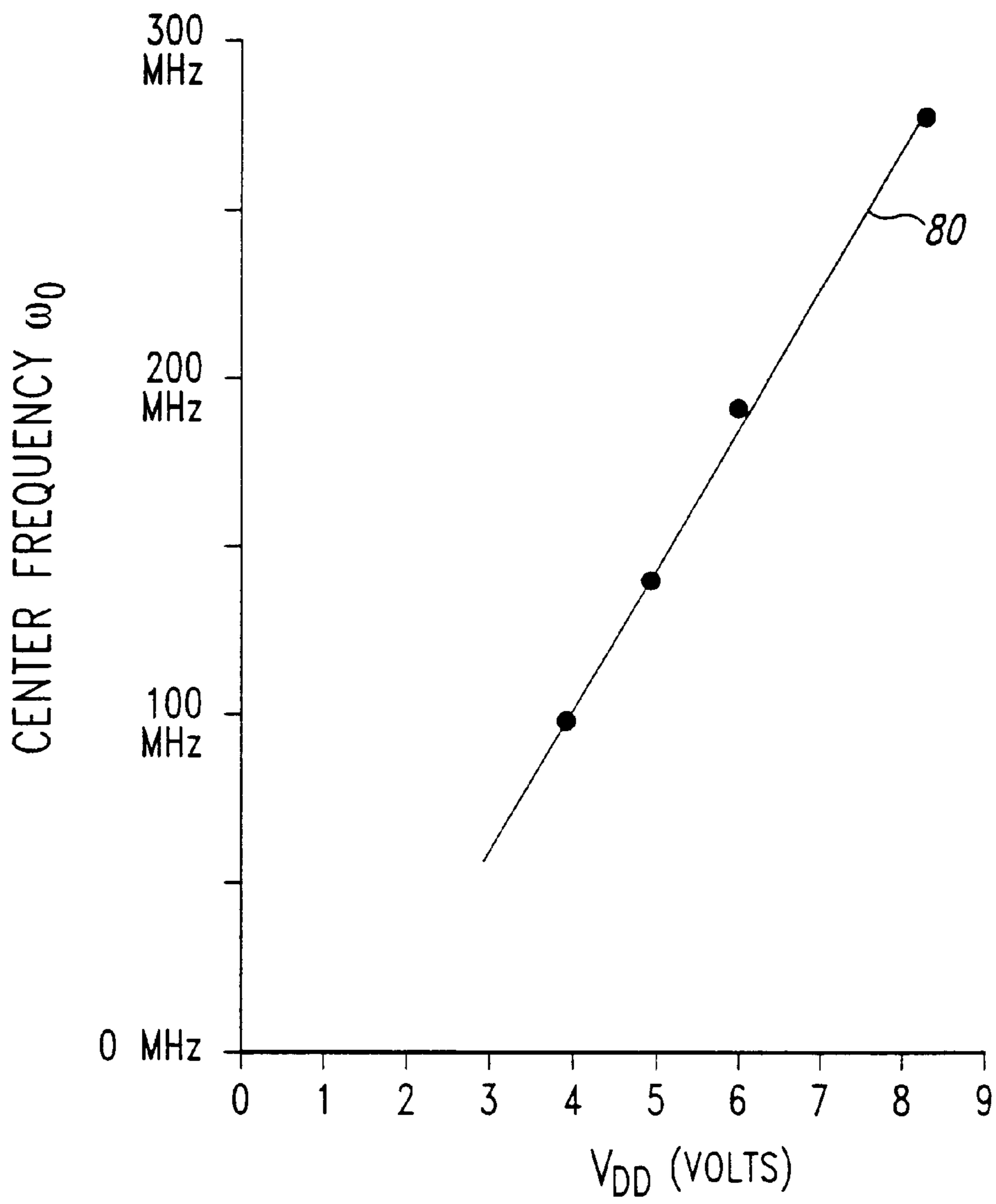
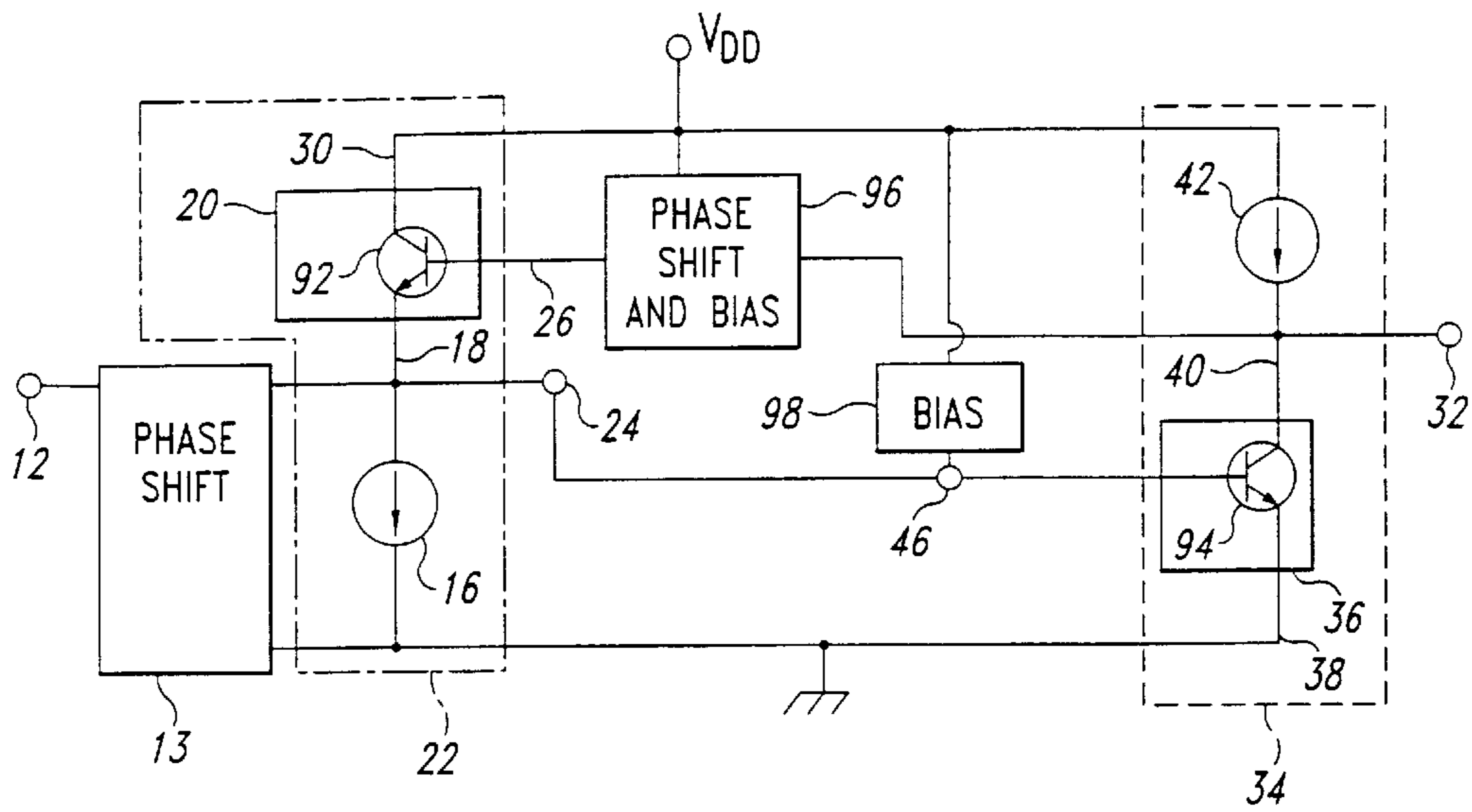


Fig. 4



90
Fig. 5

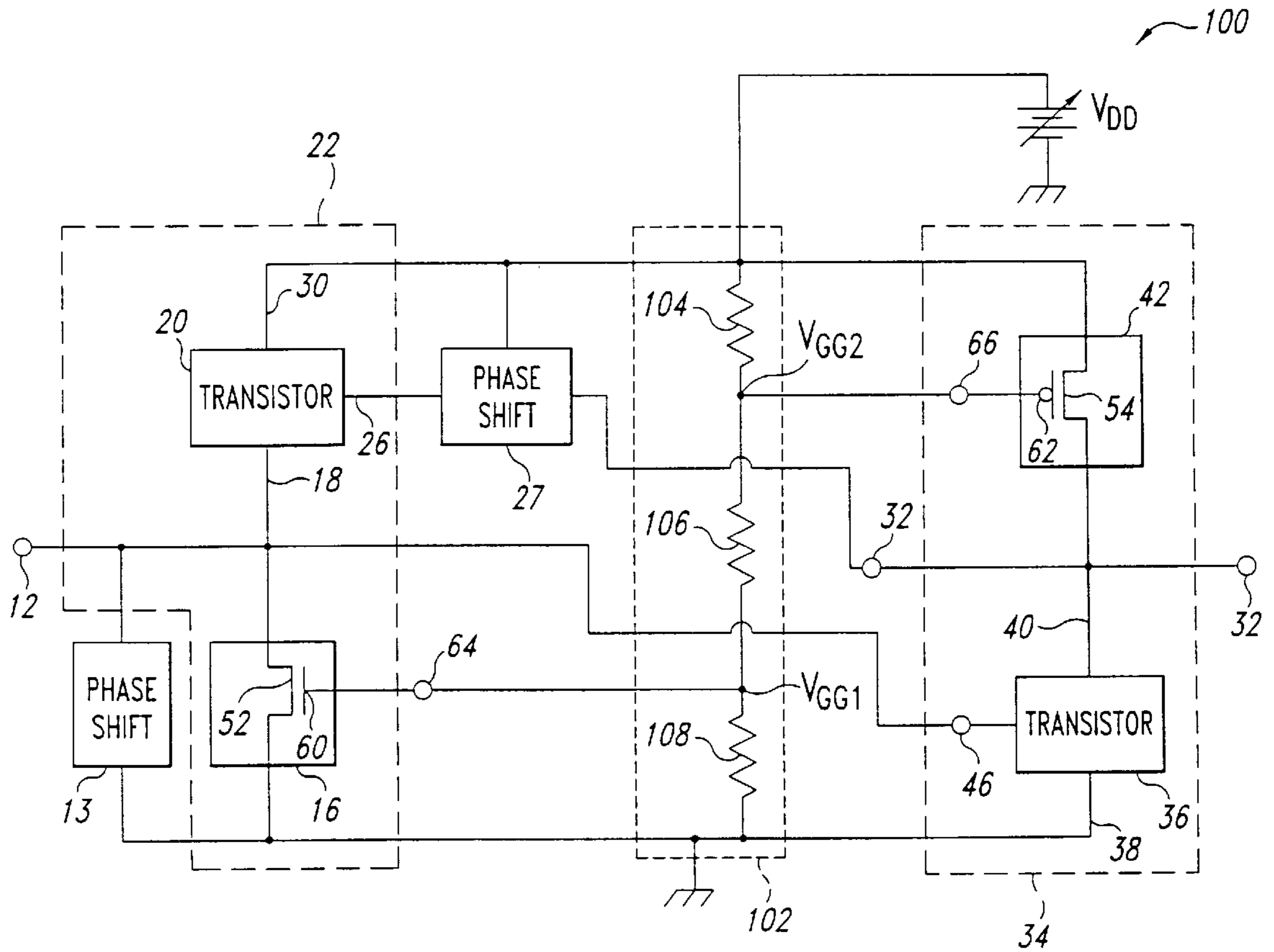


Fig. 6

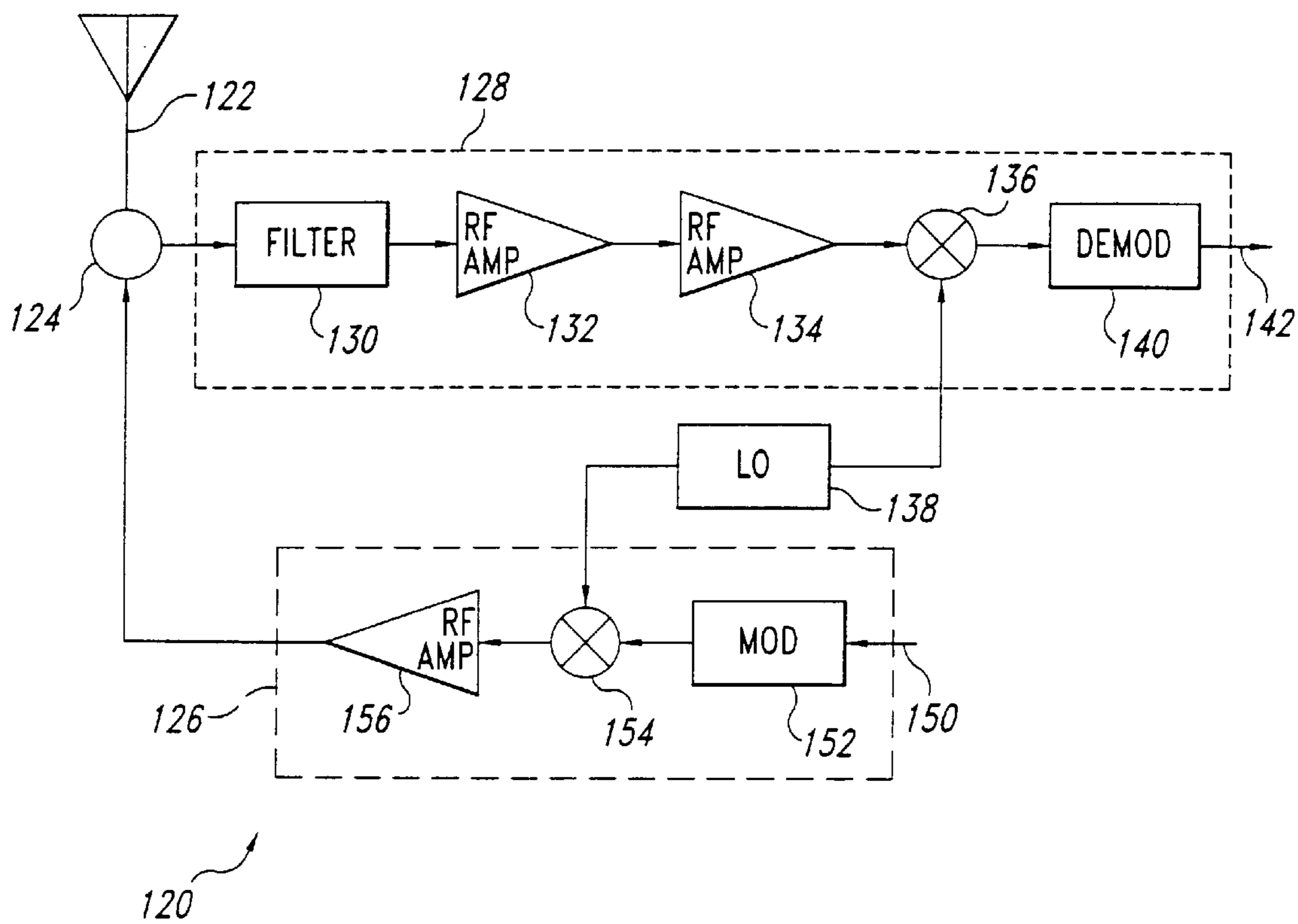


Fig. 7

MONOLITHIC FREQUENCY SELECTIVE COMPONENT AND METHOD OF OPERATING SAME

CROSS-REFERENCE TO RELATED APPLICATION

This application is a divisional of pending U.S. patent application Ser. No. 09/204,446, filed Dec. 2, 1998.

TECHNICAL FIELD

The present invention relates in general to monolithic radio frequency circuits and in particular to improved monolithic voltage tunable filters.

BACKGROUND OF THE INVENTION

Wireless communications products have become high volume consumer electronics accessories and are in increasing demand for a broad variety of applications. Features that are increasingly emphasized include reduced power consumption, small form factor, light weight and portability. Many of these products operate in a frequency range extending from about one hundred megahertz to about two gigahertz. As a result, there is a demand to integrate RF receivers and transmitters into high-yield silicon integrated circuit processes to allow a combination of analog, digital and RF functions on a single integrated circuit. "Applications for GaAs and Silicon Integrated Circuits in Next Generation Wireless Communication Systems," by L. M. Burns, IEEE JSSC, Vol. 30, No. 10, October 1995, pp. 1088-1095, discusses examples of monolithic radio receiver and transmitter functions.

Most radio receivers and transmitters require frequency selection components that rely on some form of oscillation to provide frequency selectivity. Devices such as crystals and SAWs that employ mechanical vibration to realize frequency selection also require hermetic packages having interior cavities in order to provide reliable and robust electrical characteristics, particularly in view of environmental hazards. Often, the package is more expensive than the component within it. Additionally, multiple packages are required, because the materials useful for these types of frequency selection components do not support active electronic devices, and vice versa. Further, devices that rely on mechanical oscillation also use materials having different packaging requirements than do active electronic devices.

Electronic circuits that do not rely on mechanical vibrations for frequency selection characteristics often rely instead on electrical resonances to provide frequency selectivity. Practical electrical resonators in this frequency range require a combination of capacitance and inductance. Of these, inductance is particularly difficult to realize in compact form together with reasonably high quality factor, or "Q." Q is often defined as the amount of energy stored divided by the amount of energy dissipated per cycle, but can also be defined as a center frequency divided by a three dB bandwidth of a frequency response. The latter definition is used herein in instances where the former is inapplicable.

Known approaches for realizing monolithic inductance include spiral inductors, transmission lines and bond wires. For example, "A 1.8 GHz Low-Phase-Noise Spiral-LC CMOS VCO," by J. Cranickx and M. Steyaert, 1996 Symp. on VLSI Cir. Dig. Tech. Papers, pp. 30-31 describes a spiral inductor approach that achieves a Q of 5.7 near two gigahertz. "Integrated Passive Components in MCM-Si Technology and their Applications in RF-Systems," by J.

Hartung, 1998 Int. Conf. on Multichip Modules and High Density Packaging IEEE Cat. No. 0-7803-4850-8/98, pp. 256-261, reports Qs and their frequency dependence for spiral inductors vs. substrate resistance, with highest Qs and self-resonant frequencies for spiral inductors fabricated on higher-resistivity substrates. A recent overview of spiral inductive components, entitled "Analysis, Design, and Optimization of Spiral Inductors and Transformers for Si RF IC's," by A. Niknejad and R. Meyer, IEEE JSSC, Vol. 33, No. 10, October 1998, pp. 1470-1481, gives examples of Qs having peak values around five and inductances of up to about ten nanoHenrys for spiral inductors fabricated on silicon.

Transmission line approaches to realizing monolithic inductance tend to be bulky and relatively lossy in this frequency range. Bond wires can provide Qs ranging from 11 to 15, as described in "A 1V, 1.8 GHz, Balanced Voltage-Controlled Oscillator with an Integrated Resonator," by D. A. Hitko et al., Proc. Symp. Low Power Electr. and Des., pp. 46-51 (1997). Bond wire inductors tend to be relatively large compared to other integrated circuit components, but do permit the surface area beneath them to be used to fabricate other integrated circuit elements prior to bond wire installation. Bond wire inductors also require bond pads, which are relatively large and which also preclude use of their area for other purposes. None of these approaches provide the combination of small form factor, high Q and packageability needed for many applications.

Another approach to providing a frequency selection function in monolithic form relies on impedance transformations that are possible with active circuits, i.e., circuits including transistors. U.S. Pat. No. 5,175,513, entitled "Oscillator Circuit Employing Inductive Circuit Formed of Field Effect Transistors" and issued to S. Hara, describes an example using MESFETs. U.S. Pat. No. 5,726,613, entitled, "Active Inductor," issued to H. Hayashi et al. and "A Novel Broad-Band MMIC VCO Using an Active Inductor," H. Hayashi and M. Maraguchi, IEICE Trans. Fundamentals, Vol. E81-A, No. 2, February 1998, pp. 224-229, describe similar approaches. While these approaches do provide compact circuits, they use GaAs MESFETs, which are not as manufacturable as CMOS FETs and which are not cost-competitive with silicon integrated circuits. Additionally, it is much more expensive to provide complex ancillary functions on GaAs substrates, such as may be realized using digital circuitry, than is the case with silicon substrates.

Therefore, there is a need for monolithic circuitry that provides frequency selection functions and that is compatible with cost-effective approaches to providing other circuit functions.

SUMMARY OF THE INVENTION

In one aspect, the present invention includes an active frequency selection circuit. The frequency selection circuit includes a first port presenting a frequency-dependent impedance and a first amplifier configured to provide nearly unity gain, a high input impedance and a low output impedance. The first amplifier has a first input and a first output. The first output is coupled to the first port. The frequency selection circuit includes a first phase shifter that, in one aspect, is formed by a first capacitor coupled between the first port and a reference voltage. The frequency selection circuit also includes a second amplifier configured to provide greater than unity voltage gain, a high input impedance and a low output impedance. The second amplifier has a second input coupled to the first output and a second output

coupled to the first input through a second phase shifter. In one aspect, the second phase shifter is formed from a second capacitor coupled between the second output and a reference voltage. The first and second amplifiers and the first and second phase shifters are coupled in a loop such that the frequency dependence of an impedance presented at the output of the first amplifier emulates the impedance of a parallel RLC tank circuit. The circuit is expected to provide a Q of greater than fifty at a center frequency ω_o of about five hundred megahertz. Significantly, the active frequency selection circuit may be formed as a monolithic CMOS or a BiCMOS integrated circuit. As a result, the active frequency selection circuit may be combined with other kinds of circuits, such as signal processors and digital circuits.

Voltage dependent values for parasitic impedances and admittances of the first and second amplifiers cause the center frequency ω_o to vary linearly with supply voltage. As a result, the center frequency ω_o can be swept over a range of tens or hundreds of megahertz by altering the supply voltage.

In another aspect, the frequency selection circuit forms a tuned transimpedance amplifier, with a second port coupled to the second output of the second amplifier. The second port forms an output for the transimpedance amplifier. The center frequency ω_o of the tuned transimpedance amplifier also may be varied simply by varying the supply voltage.

BRIEF DESCRIPTION OF THE DRAWINGS

FIG. 1 is a simplified schematic diagram of an inductorless, voltage-tunable filter circuit, in accordance with an embodiment of the present invention.

FIG. 2 is a simplified schematic diagram of the inductorless filter circuit of FIG. 1, showing FET's to realize the current sources and active elements of the circuit of FIG. 1, in accordance with an embodiment of the present invention.

FIG. 3 is a graph of simulated input impedance and transimpedance for the filter circuit of FIG. 2, in accordance with an embodiment of the present invention.

FIG. 4 is a graph showing simulated center frequency ω_o versus power supply voltage for the circuit of FIG. 2, in accordance with an embodiment of the present invention.

FIG. 5 is a simplified schematic diagram of another embodiment of an inductorless, voltage-tunable filter circuit, in accordance with an embodiment of the present invention.

FIG. 6 is a simplified schematic diagram of a self-biasing filter circuit that is an embodiment of the filter circuit of FIG. 2, in accordance with an embodiment of the present invention.

FIG. 7 is a simplified block diagram of a radio including tuned circuits using the circuits of FIGS. 1, 2, 5 or 6, in accordance with an embodiment of the present invention.

DETAILED DESCRIPTION OF THE INVENTION

FIG. 1 is a simplified schematic diagram of an inductorless, voltage-tunable filter circuit 10 constructed on a substrate 11, in accordance with an embodiment of the present invention. The filter circuit 10 includes an input 12 coupled to a first phase shift network 13. In one embodiment, the first phase shift network 13 is formed from a first capacitor 14 having a first capacitance C_1 coupled in shunt with the input 12. The filter circuit 10 also includes a first current source 16 coupled to a first current-carrying electrode 18 of a first transistor 20 forming a first amplifier 22. In one embodiment, the first transistor 20 is a FET

configured as a source follower amplifier. In another embodiment, the first transistor 20 is a bipolar transistor configured as an emitter follower amplifier. In either case, the first amplifier 22 provides a voltage gain at an amplifier output 24 of nearly unity, together with high input impedance and relatively low output impedance. The output 24 of the first amplifier 22 is also coupled to the input 12 to the filter circuit 10.

The first transistor 20 has a control electrode 26 coupled to a second phase shift network 27. In one embodiment, the second phase shift network 27 is formed from a second capacitor 28 having a second capacitance C_2 . The first transistor 20 has a second current-carrying electrode 30 coupled to a voltage source V_{DD} . The control electrode 26 is coupled to an output 32 of a second amplifier 34. In one embodiment, the second amplifier 34 is a common source FET amplifier. In another embodiment, the second amplifier 34 is a common emitter amplifier. The second amplifier 34 is formed from a second transistor 36 having a first current-carrying electrode 38 that is grounded and a second current-carrying electrode 40 coupled through a second current source 42 to the voltage source V_{DD} . The second transistor 36 has a control electrode 44 forming an input 46 to the second amplifier 34. The control electrode 44 is also coupled to the output 24 of the first amplifier 22.

In one embodiment, the first and second capacitors 14 and 28 are thin-film capacitors. In another embodiment, the first and second capacitors 14 and 28 are MOS capacitors, i.e., with one plate of the capacitor 14 or 28 formed as a metallic or polysilicon contact on a dielectric, such as a gate oxide, and the other plate of the capacitor 14 or 18 formed as an inversion layer of minority charge carriers in semiconducting material on another side of the dielectric.

FIG. 2 is a simplified schematic diagram of a filter circuit 50 in accordance with the embodiment of the inductorless filter circuit 10 of FIG. 1. The filter circuit 50 uses FETs 52 and 54 to realize the first and second current sources 16 and 42, and FETs 56 and 58 to realize the first and second transistors 20 and 36, respectively, of the circuit 10 of FIG. 1. Many of the components used in the embodiment of the circuit 50 of FIG. 2 are identical to components used in the embodiment of the circuit 10 of FIG. 1. Therefore, in the interest of brevity, these components have been provided with the same reference numerals, and an explanation of them will not be repeated.

For the filter circuit 50 of FIG. 2 where the first 20 and second 36 transistors of FIG. 1 are FETs 56, 58 having transconductances gm_1 and gm_2 , respectively, circuit analysis shows that, to first order, the filter circuit 50 has a center frequency ω_o :

$$\omega_o = ((gm_1 \cdot gm_2) / (C_1 \cdot C_2))^{0.5}, \quad (1)$$

and a quality factor Q:

$$Q = ((C_1 \cdot gm_2) / (C_2 \cdot gm_1))^{0.5}, \quad (2)$$

when parasitic conductances and capacitances associated with the first 56 and second 58 FETs are ignored (i.e., G_{DS} , C_{GS} etc.). The ratio of the center frequency ω_o to the Q gives the bandwidth B of the circuit as

$$B = \omega_o / Q = gm_1 / C_2. \quad (3)$$

In one embodiment, the transconductance gm_1 of the FET 56 is 5.2×10^{-5} Siemens, corresponding to a gate width of 1 micron, and the transconductance gm_2 of the FET 58 is 5×10^{-3} Siemens, corresponding to a gate width of 100

microns. When these parameters are coupled with values of $C_1=1$ picoFarad for the first capacitor **14** and $C_2=30$ femtoFarads for the second capacitor **28**, a center frequency ω_o of 468 megahertz is realized together with a Q of **57**, corresponding to a bandwidth B of about 10 megahertz. In many situations, a Q of greater than ten is desirable and a Q of greater than 20 or 25 may be extremely desirable. In general, achieving Qs in this range requires that the transconductance gm_1 of the FET **56** be less than one-tenth of the transconductance gm_2 of the FET **58** and preferably substantially less than one-tenth of the transconductance gm_2 .

In one embodiment, the FET **52** is an NMOS FET having the same gate width as an NMOS FET forming the FET **56**, while the FET **54** is a PMOS FET having the same channel width as an NMOS FET forming the FET **58**. For simplicity it is assumed the NMOS and PMOS have identical transistor characteristics. In some embodiments, the FETs **52** and **54** have their gates **60** and **62** coupled to bias voltages at nodes **64** and **66**, respectively. The bias voltages at nodes **64** and **66** may be provided by any conventional voltage source. Current sources **16** and **38** are preferred to supply current to the transistors **20** and **36**, rather than, for example, resistors, because a higher effective RF impedance is provided together with a relatively low supply voltage. In one embodiment, the circuit **10** of FIG. **1** or the circuit **50** of FIG. **2** is formed using a conventional CMOS process. In another embodiment, the circuit **10** of FIG. **1** or the circuit **50** of FIG. **2** is formed using a conventional BiCMOS process.

FIG. **3** is a graph of input impedance **70** (solid trace) and transimpedance **72** (dashed trace), and FIG. **4** is a graph showing a trace **80** representing center frequency ω_o versus power supply voltage V_{DD} , for the circuit **50** of FIG. **2**, in accordance with an embodiment of the present invention.

The source follower amplifier **22** of FIG. **2** is expected to have an input impedance associated with the input **12** having a value of $1/gm_1$ at the resonance frequency ω_o corresponding to the peak in the solid trace **70** of FIG. **3**. The impedance at the input **12** generally behaves much like a parallel RLC tank circuit and may be employed in an analogous fashion in a receiver or transmitter circuit, as is discussed below with reference to FIG. **7**. The filter circuit **50** of FIG. **2** may also be used as a transimpedance amplifier having the input **12** as an input port and using the port **32** that is coupled to the drain **40** of the second FET **36** as an output, corresponding to the dashed trace **72** of FIG. **3**. The upper trace **72** of FIG. **3** describes frequency dependence of an output voltage at the drain **40** of the second FET **36** divided by input current at the input **12**. A series of such gain stages **10** or **50** may be employed as a voltage-tunable RF amplifier chain in a TRF (tuned radio frequency) receiver or transmitter section. The trace **80** of FIG. **4** shows a linear dependence of center frequency ω_o on supply voltage V_{DD} , with a sweep rate of about 50 megahertz per volt, and also shows a broad range of frequencies over which the circuit **50** may be tuned. It will be appreciated that other frequency ranges may be realized by altering values for components in the circuit **50**.

FIG. **5** is a simplified schematic diagram of another embodiment of an inductorless, voltage-tunable filter circuit **90**, in accordance with the present invention. The filter circuit **90** includes bipolar transistors **92** and **94** as the first **20** and second **36** transistors of FIG. **1**, and may employ bipolar transistors or FETs to provide the first and second current sources **16** and **42**. When the first transistor **20** is a bipolar transistor, a base bias current must be supplied to the control electrode **26**. In one embodiment, a phase shift network **96** includes a bias source, such as a high value resistor or other conventional bias source. Similarly, when the second transistor **36** is a bipolar transistor **94**, a base bias current must be supplied. In one embodiment, the base bias current is supplied through a conventional bias network **98**,

such as a resistor. The circuit **90** may be fabricated using a conventional BiCMOS process in one embodiment.

FIG. **6** is a simplified schematic diagram of an embodiment of a self-biasing filter circuit **100** according to the embodiment of the filter circuit **50** of FIG. **2**. The self-biasing filter circuit **100** employs a resistive divider network **102** to provide a pair of gate bias voltages V_{GG1} and V_{GG2} that maintain a fixed ratio as the power supply voltage V_{DD} is varied to tune the center frequency ω_o . The resistive divider network **102** includes a first resistor **104** having a first terminal coupled to a variable supply voltage V_{DD} and a second terminal coupled to the gate **62** of the FET **54** forming the second current source **42**. A second resistor **106** has a first terminal coupled to the second terminal of the first resistor **104** and a second terminal coupled to the gate **60** of the FET **52** forming the first current source **16**. A third resistor **108** has a first electrode coupled to the second electrode of the second resistor **106** and a second electrode coupled to ground. As a result, the ratio of the gate bias voltage V_{GG1} on the FET **52** to the gate bias voltage V_{GG2} on the FET **54** is constant with changing V_{DD} . In turn, the currents through the other transistors **20** and **36** vary together as V_{DD} changes.

As a result, a simple circuit **100** is realized that provides a center frequency ω_o that may be varied over a relatively broad frequency range in response to a simple voltage change. The circuit **100** lends itself to monolithic fabrication, allowing it to be formed on an integrated circuit that is also able to support logic and other functions.

FIG. **7** is a simplified block diagram of a radio **120** including tuned RF amplifiers and/or filters using the circuits **10**, **50**, **90** or **100** of FIGS. **1**, **2**, **5** or **6**, respectively, in accordance with embodiments of the present invention. The radio **120** includes an antenna **122** for transmitting and receiving signals. The antenna **122** is coupled to an optional T/R switch or duplexer **124** that may be needed to separate signals originating in an optional transmitter section **126** from signals intended for a receiver section **128**. The receiver section **128** may include an optional filter **130** that accepts RF input signals from the antenna **122** and typically includes one or more radio frequency amplifiers **132**, **134** (marked "RF AMP" in FIG. **7**) coupled in series. A mixer **136** mixes signals from the amplifiers RF AMP **132**, **134** with signals from a local oscillator LO **138** to provide baseband or IF signals that are then processed and demodulated by a signal processor DEMOD **140** to provide an output signal at an output **142**. The signal at the output **142** may be an IF signal, a visual or audible annunciation, for example when the receiver section **128** forms a portion of a paging device or portable telephone, or may be digital data or voice signals in other applications.

In those applications where the transmitter section **126** is also a portion of the radio **120**, input data from an input **150** is processed in a signal processor MOD **152** that typically includes a modulator and that may include other functions. An output signal from the signal processor MOD **152** is mixed with a signal from the local oscillator LO **138** in a mixer **154** to provide radio frequency signals. The radio frequency signals are typically amplified in a radio frequency amplifier RF AMP **156** and are routed to the antenna **122** for transmission.

In the radio **120**, the optional filter **130** may be a conventional passive filter or may be any of the circuits **10**, **50**, **90** or **100** of FIGS. **1**, **2**, **4** or **6**, respectively. In some applications, a passive filter offers intermodulation advantages, while in others, noise figure is a dominating concern, requiring a low noise gain block coupled to the antenna **122**. The radio frequency amplifiers RF AMP **132**, **134**, **156** may be conventional RF amplifiers that are tuned by having the input **12** (FIGS. **1**, **2**, **4**, **6**) coupled to the signal path or may be transimpedance amplifiers having inputs **12**

and outputs **32**. Either topology may be employed to provide a tuned radio frequency amplifier chain. In either topology, independent control of the supply voltages allows independent adjustment of the center frequencies of the radio frequency amplifiers RF AMP **132**, **134**, **156**.

In some embodiments, a conventional digital-to-analog converter (not illustrated) may be employed to supply the variable supply voltage V_{DD} under control of a conventional microprocessor (not illustrated). This allows the center frequency ω_c to be set in response to external commands or in response to variables sensed within the system containing the circuits **10**, **50**, **90** or **100** or the radio **120**.

An advantage to radios **120** using the circuits **10**, **50**, **90** or **100** is that many, if not all, of the functions of the radio **120** may be realized through one or more integrated circuits. As a result, the radio **120** may be manufactured using less labor together with improved footprint, reduced weight, greater reliability and reduced power consumption, and in a very compact package. The radio **120** may also be combined with other functional blocks in a single integrated circuit.

From the foregoing it will be appreciated that, although specific embodiments of the invention have been described herein for purposes of illustration, various modifications may be made without deviating from the spirit and scope of the invention. Accordingly, the invention is not limited except as by the appended claims.

What is claimed is:

1. A monolithic frequency selective component comprising:

- a substrate;
- a first port having a voltage-variable frequency-dependent input impedance;
- a first FET amplifier formed on the substrate, configured as a source follower and having an output coupled to the first port, the first FET amplifier including:
 - a first FET having a first gate width and including a source coupled to the output of the first FET amplifier, a drain coupled to a power supply and a gate coupled to an input to the first FET amplifier; and
 - a second FET having the first gate width and including a source coupled to ground, a gate and a drain coupled to the source of the first FET;
- a first phase shift network formed on the substrate and coupled to the first port;
- a second phase shift network formed on the substrate and coupled to the input to the first FET amplifier; and
- a second FET amplifier formed on the substrate and having an output coupled to the second phase shift network and an input coupled to the output of the first FET amplifier, the second FET amplifier including:
 - a third FET having a second gate width and including a source coupled to ground, a drain and a gate coupled to the input to the second FET amplifier; and
 - a fourth FET having the second gate width and including a drain coupled to the power supply, a gate and a source coupled to the drain of the second FET; and
- a bias network coupled to the gates of the second and fourth FETs.

2. The component of claim **1**, wherein the first gate width is about one one-hundredth of the second gate width.

3. The component of claim **1**, wherein:

- the first phase shift network includes a thin-film capacitor having a first electrode coupled to the first port and a second electrode coupled to RF ground; and
- the second phase shift network includes a thin-film capacitor having a first electrode coupled to the input of

the first FET amplifier and a second electrode coupled to RF ground.

4. The component of claim **1**, wherein the bias network comprises:

- a first resistor having a first electrode coupled to ground and a second electrode coupled to the gate of the second FET;
- a second resistor having a first electrode coupled to the second electrode of the first resistor and a second electrode coupled to the gate of the fourth FET; and
- a third resistor having a first electrode coupled to the gate of the fourth FET and a second electrode coupled to a power supply.

5. The component of claim **1** wherein the first, second and third FETs are n-channel FETs and the fourth FET is a p-channel FET.

6. The component of claim **1** wherein the first FET has a first transconductance and the third FET has a second transconductance that is more than ten times the first transconductance.

7. The component of claim **1** wherein the first FET has a first transconductance and the third FET has a second transconductance approximately one hundred times the first transconductance.

8. The component of claim **1**, further comprising a second port coupled to the output of the second FET amplifier, where the first port forms a filter input and the second port forms a filter output.

9. The component of claim **1** wherein the first FET has a first transconductance gm_1 , the third FET has a second transconductance gm_2 , the first phase shift network includes a first capacitor having a capacitance C_1 , the second phase shift network includes a second capacitor having a capacitance C_2 and the component has a quality factor $Q = ((C_1 \cdot gm_2) / (C_2 \cdot gm_1))^{0.5}$ that is greater than 10.

10. The component of claim **1** wherein the first and second FET amplifiers are formed by a CMOS process.

11. The component of claim **1** wherein the first and second FET amplifiers are formed by a BiCMOS process.

12. A method of operating a monolithic frequency selection component comprising:

- providing a first FET amplifier configured as a source follower and having a first transconductance gm_1 ;
- providing a second FET amplifier configured as a common source amplifier and having a second transconductance gm_2 ;
- providing a first capacitor having a first lead coupled to an output of the second FET amplifier and to an input of the first FET amplifier, the first capacitor having a capacitance C_1 ;
- providing a second capacitor having a second capacitance C_2 and including a first lead coupled to an output of the first FET amplifier; and
- setting a supply voltage for the first and second FET amplifiers to a voltage that causes a frequency response at the output of the first FET amplifier to have a first center frequency ω_{o1} of approximately $((gm_1 \cdot gm_2) / (C_1 \cdot C_2))^{0.5}$.

13. The method of claim **12** further comprising setting a Q of the frequency response to be approximately $Q = ((C_1 \cdot gm_2) / (C_2 \cdot gm_1))^{0.5}$.

14. The method of claim **13** wherein the act of setting a Q includes setting the Q to be greater than 10.

15. The method of claim **12**, further comprising resetting the supply voltage to cause the frequency response at the output of the first FET amplifier to have a second center frequency ω_{o2} different than the first center frequency ω_{o1} .

UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

PATENT NO. : 6,362,692 B2
DATED : March 26, 2002
INVENTOR(S) : Leonard Forbes

Page 1 of 1

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Title page,

Item [56], please add the following references in the section titled "**References Cited**":

-- 4,524,332 6/1985 Gay 330/294 --

Column 7,

Line 62, reads "claim 1," should read -- claim 1 --

Column 8,

Line 3, reads "claim 1," should read -- claim 1 --

Line 59, reads "claim 12" should read -- claim 12, --

Signed and Sealed this

Tenth Day of September, 2002

Attest:



Attesting Officer

JAMES E. ROGAN
Director of the United States Patent and Trademark Office